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**Product data sheet** 

## 1. General description

Planar passivated four quadrant triac in a SOT1292 (IITO3P) package intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. This triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)}$  = 150 °C). It is used in applications where "high junction operating temperature capability" is required.

### 2. Features and benefits

- High current TRIAC
- Low thermal resistance
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- High voltage capability
- Planar passivated for voltage ruggedness and reliability
- Insulated tab rated at 2500 V rms

## 3. Applications

- · High current / high surge applications
- · High power / industrial controls -- e.g. heating, motors, lighting

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit
Absolute	maximum rating			
$V_{DRM}$	repetitive peak off-state voltage	·		V
I <sub>T(RMS)</sub>	RMS on-state current	square-wave pulse; T <sub>mb</sub> ≤ 105 °C; Fig. 1; Fig. 2; Fig. 3	40	Α
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p = 20 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$ ; Fig. 4; Fig. 5	400	Α
		full sine wave; $t_p = 16.7 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$ ;	440	Α
T <sub>j</sub>	junction temperature		150	°C

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static characteristics						
l <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ G+$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-$ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G+} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	70	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	80	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 56.6 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.2	1.5	V
Dynamic	characteristics		'			
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_j$ = 125 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	750	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	500	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; I_{T(RMS)} = 20\text{A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; gate open circuit}$	20	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 150 \text{ °C}; I_{T(RMS)} = 20\text{A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ gate open circuit}$	10	-	-	A/ms

# 5. Pinning information

**Table 2. Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1		T2—T1
2	T2	main terminal 2		G sym051
3	G	gate		Symoon
mb	n.c.	mounting base; isolated	IITO3P (SOT1292)	

# 6. Ordering information

**Table 3. Ordering information** 

Type number	Package		
	Name	Description	Version
BTA41-600B	IITO3P	plastic single-ended through-hole package; isolated heatsink mounted; 1 mounting hole; 3-lead TO3P	SOT1292

## 7. Marking

Table 4. Marking codes

Type number	Marking codes
BTA41-600B	BTA41-600B

# 8. Limiting values

#### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		600	V
I <sub>T(RMS)</sub>	RMS on-state current	full sine wave; T <sub>mb</sub> ≤ 105°C; <u>Fig. 1;</u> <u>Fig. 2; Fig. 3</u>	40	А
I <sub>TSM</sub>	non-repetitive peak on- state current	full sine wave; $t_p$ = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	400	А
		full sine wave; $t_p = 16.7 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$ ;	440	А
l <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10ms; sine wave	800	A²/s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 150mA	150	A/µs
I <sub>GM</sub>	peak gate current	t <sub>p</sub> = 20µs	8	А
P <sub>GM</sub>	peak gate power	t <sub>p</sub> = 20μs	40	W
P <sub>G(AV)</sub>	average gate power	over any 20 ms period	1	W
T <sub>stg</sub>	storage temperature		-40 to 150	°C
T <sub>j</sub>	junction temperature		150	°C

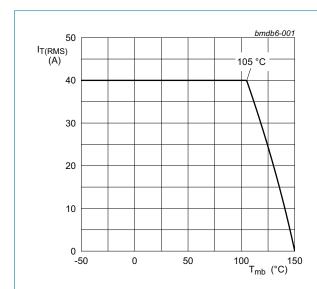


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

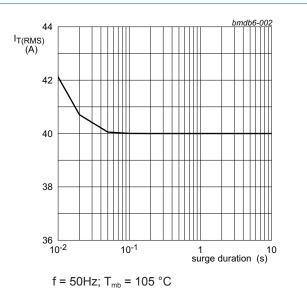


Fig. 2. RMS on-state current as a function of surge duration; maximum values

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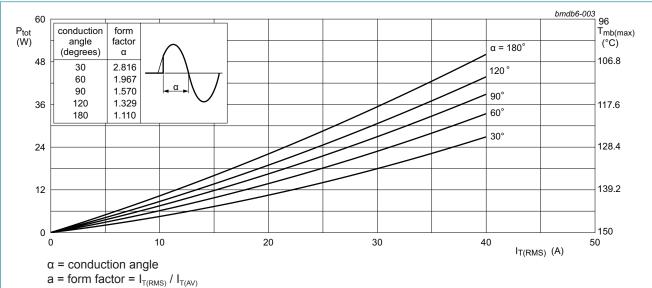


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

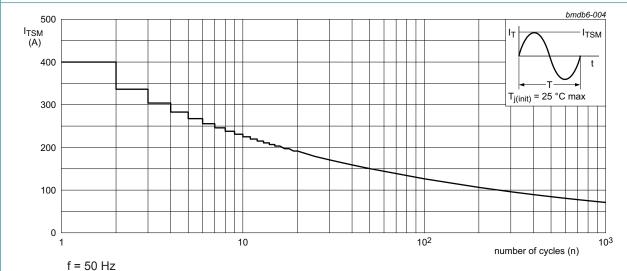
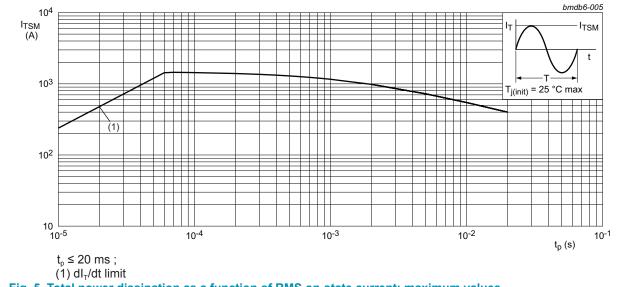


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



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## 9. Thermal characteristics

#### Table 5. Thermal characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 6		-	-	0.9	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient free air	in free air		-	55	-	K/W

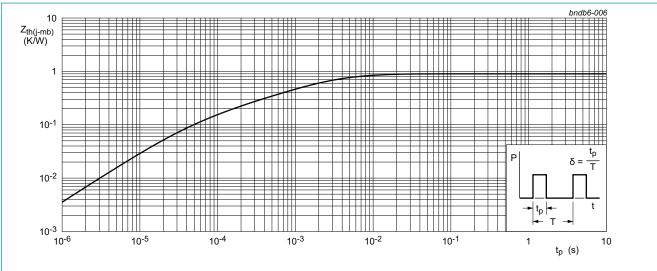


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

### 10. Isolation characteristics

**Table 6. Isolation characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>isol(RMS)</sub>	RMS isolation voltage	from all terminal to external heatsink; sinusoidal waveform; clean and dust free; 50 Hz $\leq$ f $\leq$ 60 Hz; RH $\leq$ 65 %; $T_h = 25$ °C	-	-	2500	V

## 11. Characteristics

**Table 7. Characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } Fig. 7$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	50	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$	-	-	70	mA
l <sub>L</sub>	latching current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	100	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	160	mA
	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	100	mA	
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2- \text{ G+;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 8}}$	-	-	100	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	80	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 56.6 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.2	1.5	V
V <sub>GT</sub> gate trigger voltage		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C;}$ Fig. 11	-	8.0	1.3	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 \text{ °C};$ Fig. 11	0.2	0.45	-	V
l <sub>D</sub>	off-state current	V <sub>D</sub> = 600 V; T <sub>j</sub> = 25 °C	-	-	10	μA
		V <sub>D</sub> = 600 V; T <sub>j</sub> = 150 °C	-	-	2.5	mA
Dynamic (	characteristics					
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 536 V; $T_{j}$ = 125 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	750	-	-	V/µs
		$V_{DM}$ = 536 V; $T_{j}$ = 150 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	500	-	-	V/µs
dI <sub>com</sub> /dt	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 20\text{A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; gate open circuit}$	20	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 20\text{A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; gate open circuit}$	10	-	-	A/ms

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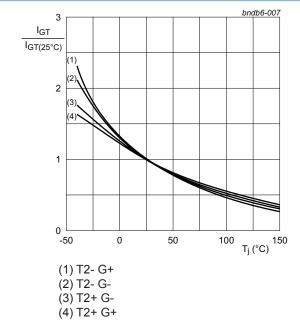


Fig. 7. Normalized gate trigger current as a function of junction temperature

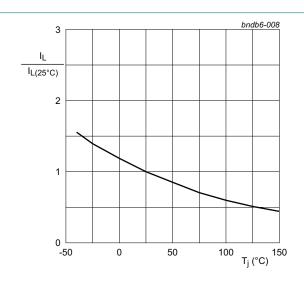


Fig. 8. Normalized latching current as a function of junction temperature

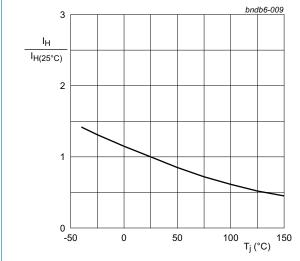
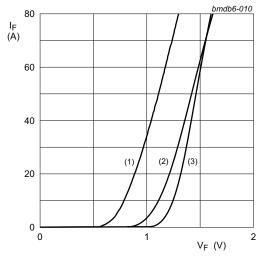


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o = 1.063 \text{ V}; R_s = 0.0074 \Omega$ 

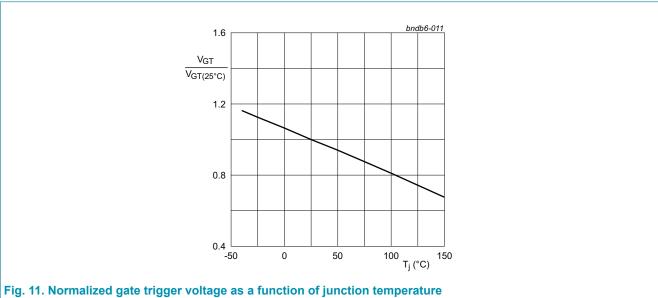
(1)  $T_j = 150$  °C; typical values (2)  $T_j = 150$  °C; maximum values

(3)  $T_i = 25$  °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

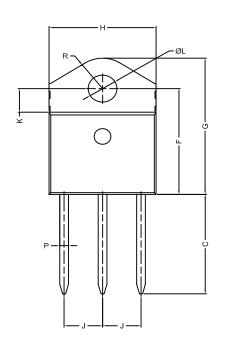
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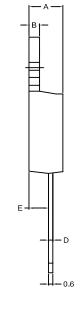
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# 12. Package outline







Uni-	ţ	Α	В	С	D	Е	F	G	Н	J	К	١	Р	R
mm	min	4.75	1.45	14.35	0.50	2.70	15.80	20.40	15.10	5.40	3.40	4.08	1.20	4.6
	max	4.95	1.55	15.60	0.70	2.90	16.50	21.10	15.50	5.65	3.65	4.17	1.40	(typ.)

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## 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 10 July 2017

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